Docket No.

206169US99

IN THE TATES PATENT AND TRADEMARK OFFIC

IN RE APPLICATION OF:

JAMAL RAMDANI ET AL

SERIAL NO:

09/766,046

GAU:

2815

FILED:

JANUARY 19, 2001

EXAMINER: BAUMEISTER

FOR:

STRUCTURE AND METHOD FOR FABRICATING GAN DEVICES UTILIZING THE FORMATION

COMPLIANT SUBSTRATE

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFF

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from aforeign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement. 3

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

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SHEET 1 OF 5

ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 206169US99 09/766,046 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Jamal RAMDANI, et al. **FILING DATE GROUP** 2815 January 19, 2001 **U.S. PATENT DOCUMENTS** SUB FILING DATE **EXAMINER** DOCUMENT DATE NAME **CLASS** IF APPROPRIATE INITIAL NUMBER CLASS UT 06/18/96 Macdonald et al. 5,528,209 UV 5,998,781 12/07/99 Vawter et al. UW 6,110,813 08/29/00 Ota et al. UX 09/17/02 6,452,232 B1 Adan UY 6,049,110 04/11/00 Koh 09/24/96 Hu et al. UΖ 5,559,368 VA 6,392,253 B1 05/21/02 Saxena VΒ 12/17/96 Davis et al. 5,585,288 VC 12/07/93 Vernon 5,268,327 VD 03/06/01 Nabatame et al. 6,198,119 B1 VΕ 6,113,225 09/05/00 Miyata et al. VF 11/16/93 Grudkowski et al. 5.262.659 VG 6,239,012 B1 05/29/01 Kinsman VΗ 6,297,598 10/02/01 Wang et al. VΙ 2002/140012 10/03/02 Droopad VJ 4,866,489 09/12/89 Yokogawa et al. 06/27/00 Yokota et al. VK 6,080,378 VL 5,508,554 04/16/96 Takatani et al. VM 11/05/02 Shanley 6,477,285 B1 VN 4,695,120 09/22/87 Holder VO 5,882,948 03/16/99 Jewell VP 5,574,589 11/12/96 Feuer et al. 04/23/96 VQ 5,510,665 Conley 02/14/89 VR 4,804,866 Akiyama vs 5,057,694 10/15/91 Idaka et al. VT 06/03/97 Pique et al. 5,635,453 VU 02/17/98 Roeder et al. 5,719,417 12/07/99 Yokoyama et al. W 5,998,819 Date Considered Examiner

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through?citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

ATTY DOCKET NO. SERIAL NO. Form PTO 1449 EPARTMENT OF COMMERCE (Modified) TENT AND TRADEMARK OFFICE 206169US99 09/766,046 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Jamal RAMDANI, et al. **FILING DATE GROUP** January 19, 2001 2815 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB **FILING DATE** DATE NAME **CLASS** INITIAL CLASS IF APPROPRIATE NUMBER W 2002/0079576 06/27/02 Seshan VX 5,148,504 09/15/92 Levi et al. 12/26/02 VY 2002/0195610 A1 Klosowiak VΖ 5,477,363 12/19/95 Matsuda WA 5,905,571 05/18/99 Butler et al. 10/29/96 WB 5,570,226 Ota wc 5,087,829 02/11/92 Ishibashi et al. WD 2001/0020278 A1 09/06/01 Saito WE 6,496,469 B1 12/17/02 Uchizaki Doi et al. WF 5,679,947 10/21/97 WG 2001/0036142 A1 11/01/01 Kadowaki et al. WH 5,446,719 08/29/95 Yoshida et al. WI 5,831,960 11/03/98 Jiang et al. 12/02/97 WJ McKee et al. 5,693,140 WK 6,376,337 B1 04/23/02 Wang et al. WL 12/04/79 4,177,094 Kroon WM 5,216,359 06/01/93 Makki et al. Nashimoto et al. WN 6,307,996 B1 10/23/01 WO 5,371,621 12/06/94 Stevens WP 2002/0145168 A1 10/10/02 Bojarczuk, Jr et al. WQ 11/02/71 Anderson 3,617,951 WR 5,838,053 11/17/98 Bevan et al. ws 5,684,302 11/04/97 Wersing et al. WT 5,959,308 09/28/99 Shichijo et al. WU 11/08/94 5,362,972 Yazawa et al. TI WV 5,864,171 01/26/99 Yamamoto et al. ww 5.028.563 07/02/91 Feit et al. WX 08/10/99 Domash 5,937,115 Examiner **Date Considered**

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ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 RADEMARY (Modified) 206169US99 09/766,046 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Jamal RAMDANI, et al. **FILING DATE GROUP** January 19, 2001 2815 **U.S. PATENT DOCUMENTS** EXAMINER **DOCUMENT** SUB **FILING DATE** CLASS DATE NAME INITIAL NUMBER CLASS IF APPROPRIATE WY 5,878,175 03/02/99 Sonoda et al. wz 4,801,184 01/31/89 Revelli 08/18/92 Okazaki et al. XA 5,140,387 04/25/95 Okada et al. XB 5,410,622 XC 6,064,783 05/16/00 Congdon et al. XD 06/30/98 Collins et al. 5,772,758 09/09/97 XΕ 5,666,376 Cheng XF 5,976,953 11/02/99 Zavracky et al. XG 5,578,162 11/26/96 D'Asaro.et.al. XH 5,585,167 12/17/96 Satoh et al. ΧI 10/07/97 Nakamura et al. 5,674,813 ΧJ 11/12/96 5,574,296 Park et al. XK 6,504,189 01/07/03 Matsuda et al. 11/16/99 XL 5,987,196 Noble ΧM XN XO ΧP XQ XR XS XT ΧU ΧV xw XXXY ΧZ Date Considered Examiner

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Form PTO 1449 (Modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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Jamal RAMDANI, et al.

FILING DATE
January 19, 2001

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
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	CBD	EP 0 860 913	08/26/95	EUROPE				
	CBE	5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT				
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